

Application

- Half-bridge and full-bridge topologies
- Synchronous rectifier applications
- Resonant mode power supplies
- DC/DC converters
- DC/AC Inverters

HEXFET® Power MOSFET

V_{DSS}	40V
R_{DS(on)} typ.	0.95mΩ
	max 1.25mΩ
I_D (Silicon Limited)	265A①
I_D (Package Limited)	100A①

Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and di/dt Capability
- Lead-Free, RoHS Compliant



Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFH7084PbF	PQFN 5mm x 6mm	Tape and Reel	4000	IRFH7084TRPbF

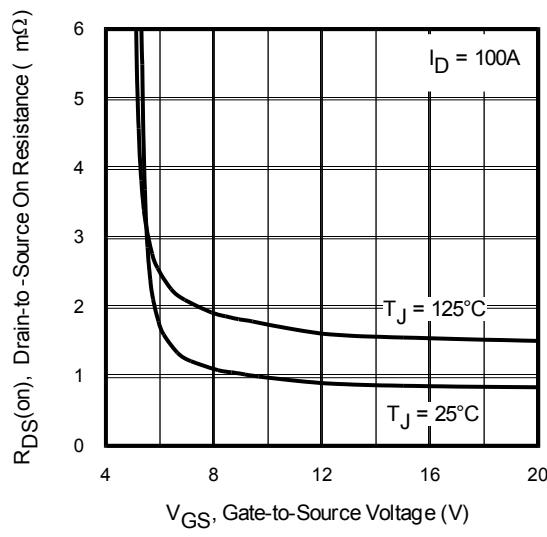


Fig 1. Typical On-Resistance vs. Gate Voltage

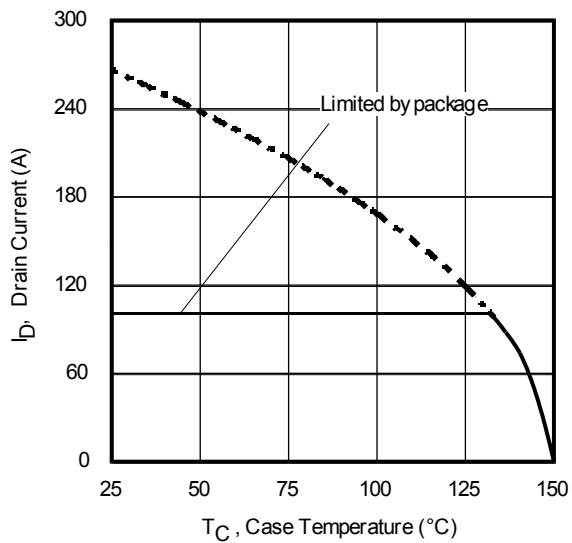


Fig 2. Maximum Drain Current vs. Case Temperature

Absolute Maximum Rating

Symbol	Parameter	Max.	Units
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	40	A
$I_D @ T_{C(Bottom)} = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	265①	
$I_D @ T_{C(Bottom)} = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	170①	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Package Limited)	100①	
I_{DM}	Pulsed Drain Current ①	400	
	Linear Derating Factor	1.25	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C

Avalanche Characteristics

E_{AS} (Thermally limited)	Single Pulse Avalanche Energy ③	185	mJ
E_{AS} (tested)	Single Pulse Avalanche Energy Tested Value ⑨	370	
I_{AR}	Avalanche Current ②	See Fig 14, 15, 23a,	A
E_{AR}	Repetitive Avalanche Energy ②		mJ

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$ (Bottom)	Junction-to-Case ⑧	0.5	0.8	°C/W
$R_{\theta JC}$ (Top)	Junction-to-Case ⑧	—	21	
$R_{\theta JA}$	Junction-to-Ambient ⑩	—	35	
$R_{\theta JA}$ (<10s)	Junction-to-Ambient ⑩	—	20	

Static @ $T_J = 25^\circ C$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.034	—	V/°C	Reference to 25°C, $I_D = 1mA$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	0.95	1.25	mΩ	$V_{GS} = 10V, I_D = 100A$
$V_{GS(th)}$	Gate Threshold Voltage	2.2	—	3.9	V	$V_{DS} = V_{GS}, I_D = 150\mu A$
I_{DSS}	Drain-to-Source Leakage Current	—	—	1.0	μA	$V_{DS} = 40 V, V_{GS} = 0V$
		—	—	150	μA	$V_{DS} = 40V, V_{GS} = 0V, T_J = 125^\circ C$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-100	nA	$V_{GS} = -20V$
R_G	Gate Resistance	—	1.4	—	Ω	

Notes:

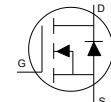
- ① Calculated continuous current based on maximum allowable junction temperature. Package is limited to 100A by production test capability.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ Limited by T_{Jmax} , starting $T_J = 25^\circ C$, $L = 0.037mH$, $R_G = 50\Omega$, $I_{AS} = 100A$, $V_{GS} = 10V$.
- ④ $I_{SD} \leq 100A$, $dI/dt \leq 994A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq 150^\circ C$.
- ⑤ Pulse width $\leq 400\mu s$; duty cycle $\leq 2\%$.
- ⑥ C_{oss} eff. (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑦ C_{oss} eff. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑧ R_θ is measured at T_J approximately 90°C.
- ⑨ This value determined from sample failure population, starting $T_J = 25^\circ C$, $L = 0.037mH$, $R_G = 50\Omega$, $I_{AS} = 100A$, $V_{GS} = 10V$.
- ⑩ When mounted on 1 inch square PCB (FR-4). Please refer to AN-994 for more details:
<http://www.irf.com/technical-info/appnotes/an-994.pdf>

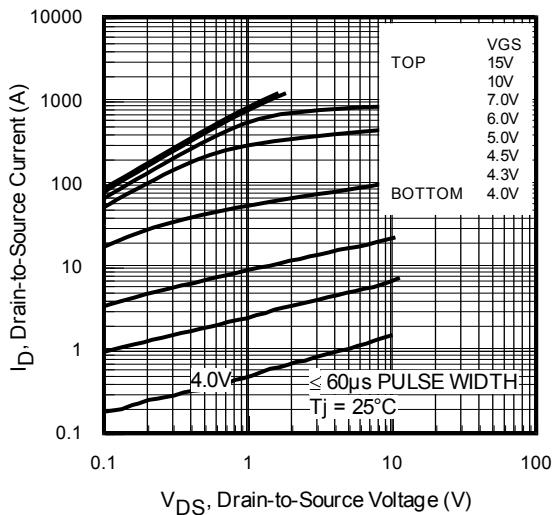
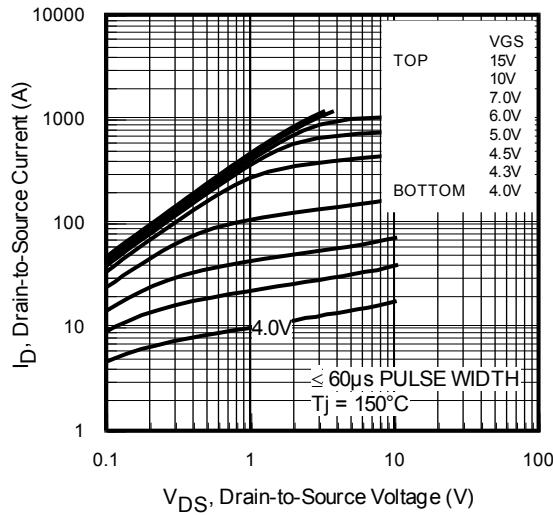
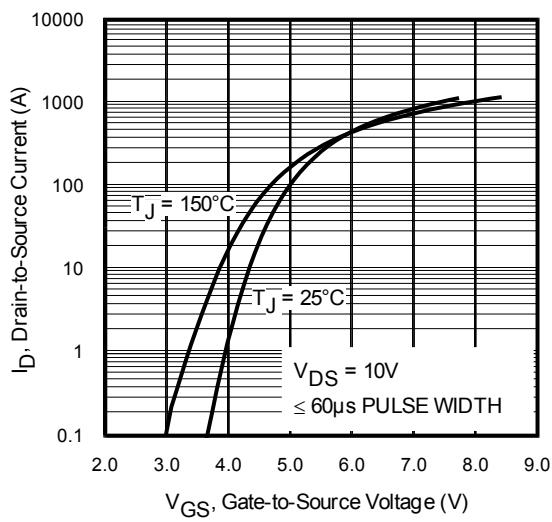
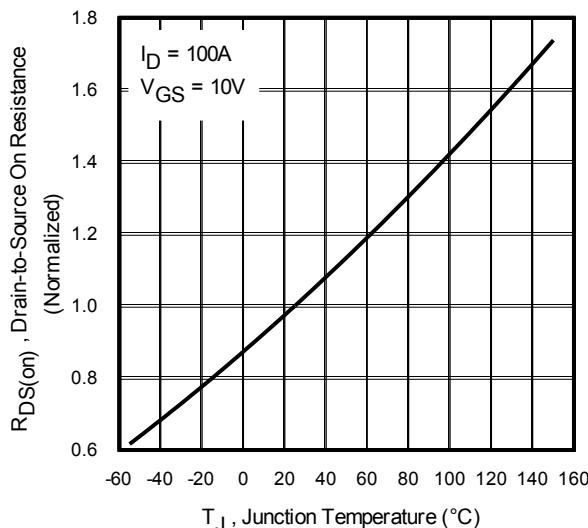
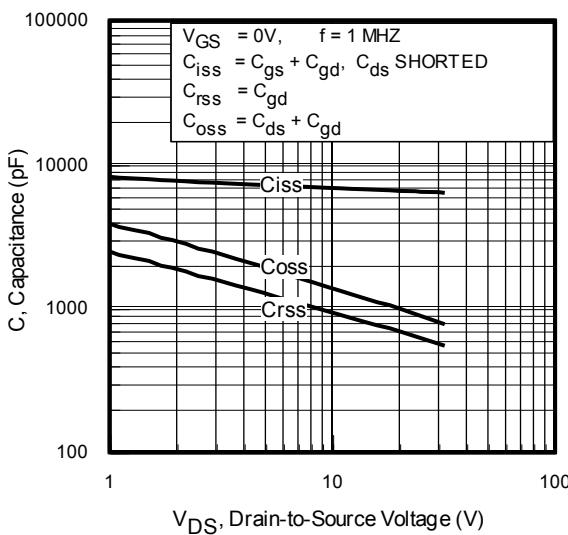
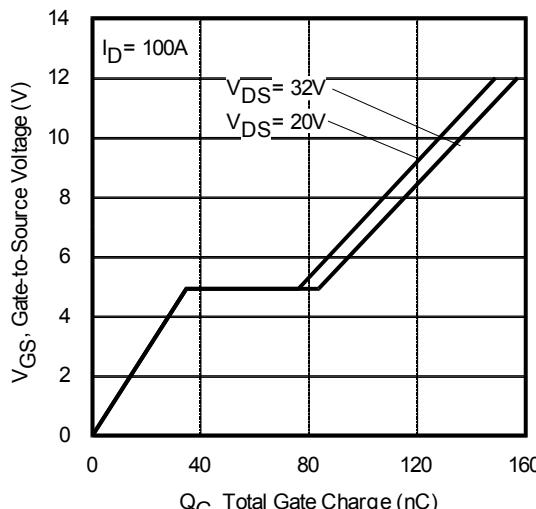
Dynamic Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
g_{fs}	Forward Transconductance	120	—	—	S	$V_{DS} = 10\text{V}$, $I_D = 100\text{A}$
Q_g	Total Gate Charge	—	127	190	nC	$I_D = 100\text{A}$
Q_{gs}	Gate-to-Source Charge	—	35	—		$V_{DS} = 20\text{V}$
Q_{gd}	Gate-to-Drain Charge	—	41	—		$V_{GS} = 10\text{V}$
Q_{sync}	Total Gate Charge Sync. ($Q_g - Q_{gd}$)	—	195	—		
$t_{d(on)}$	Turn-On Delay Time	—	16	—	ns	$V_{DD} = 20\text{V}$
t_r	Rise Time	—	31	—		$I_D = 30\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	64	—		$R_G = 2.7\Omega$
t_f	Fall Time	—	34	—		$V_{GS} = 10\text{V}$ ⑤
C_{iss}	Input Capacitance	—	6560	—	pF	$V_{GS} = 0\text{V}$
C_{oss}	Output Capacitance	—	940	—		$V_{DS} = 25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	650	—		$f = 1.0\text{MHz}$, See Fig.5
$C_{oss\ eff.(ER)}$	Effective Output Capacitance (Energy Related)	—	1120	—		$V_{GS} = 0\text{V}$, $V_{DS} = 0\text{V}$ to 32V ⑦ See Fig.11
$C_{oss\ eff.(TR)}$	Output Capacitance (Time Related)	—	1300	—		$V_{GS} = 0\text{V}$, $V_{DS} = 0\text{V}$ to 32V ⑥

Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I_s	Continuous Source Current (Body Diode)①	—	—	100①	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{sm}	Pulsed Source Current (Body Diode) ①	—	—	400		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}$, $I_s = 100\text{A}$, $V_{GS} = 0\text{V}$ ⑤
dv/dt	Peak Diode Recovery dv/dt ④	—	4.5	—	V/ns	$T_J = 150^\circ\text{C}$, $I_s = 100\text{A}$, $V_{DS} = 40\text{V}$ ⑤
t_{rr}	Reverse Recovery Time	—	36	—	ns	$T_J = 25^\circ\text{C}$ $V_{DD} = 34\text{V}$
		—	37	—		$T_J = 125^\circ\text{C}$ $I_F = 100\text{A}$,
Q_{rr}	Reverse Recovery Charge	—	38	—	nC	$T_J = 25^\circ\text{C}$ $di/dt = 100\text{A}/\mu\text{s}$ ⑤
		—	40	—		$T_J = 125^\circ\text{C}$
I_{RRM}	Reverse Recovery Current	—	1.7	—	A	$T_J = 25^\circ\text{C}$



**Fig 3.** Typical Output Characteristics**Fig 4.** Typical Output Characteristics**Fig 5.** Typical Transfer Characteristics**Fig 6.** Normalized On-Resistance vs. Temperature**Fig 7.** Typical Capacitance vs. Drain-to-Source Voltage**Fig 8.** Typical Gate Charge vs. Gate-to-Source Voltage

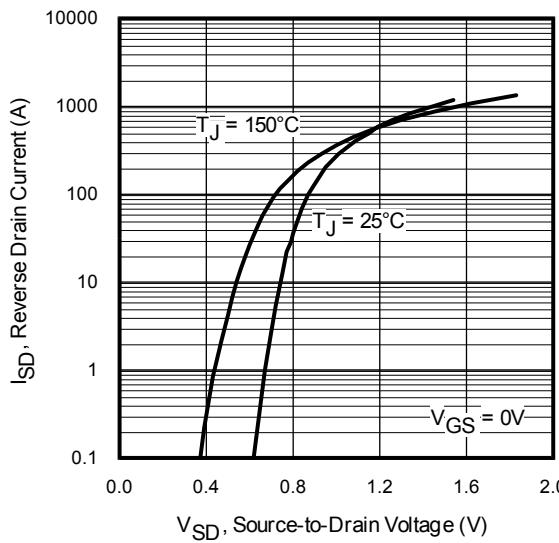


Fig 9. Typical Source-Drain Diode Forward Voltage

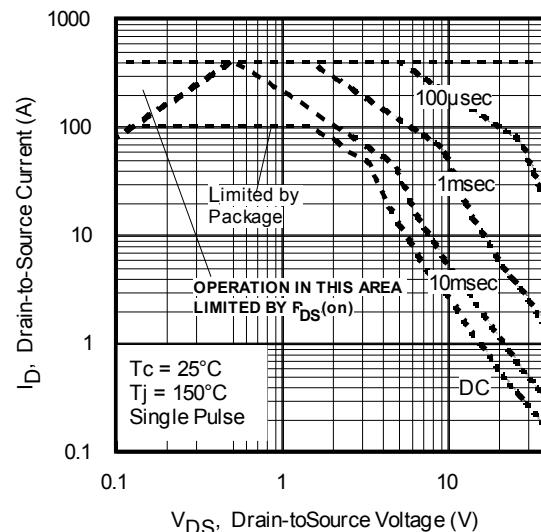


Fig 10. Maximum Safe Operating Area

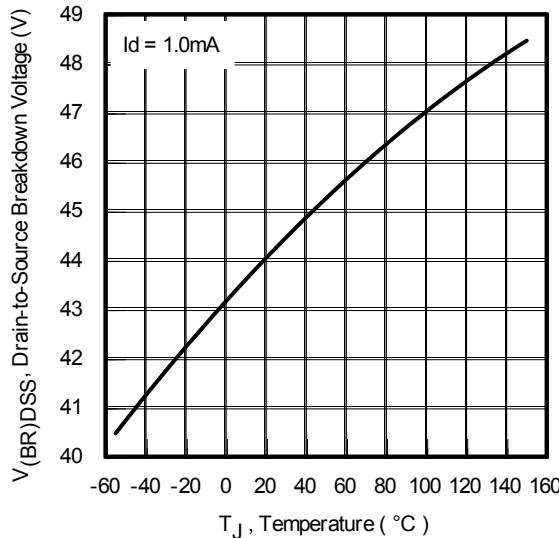


Fig 11. Drain-to-Source Breakdown Voltage

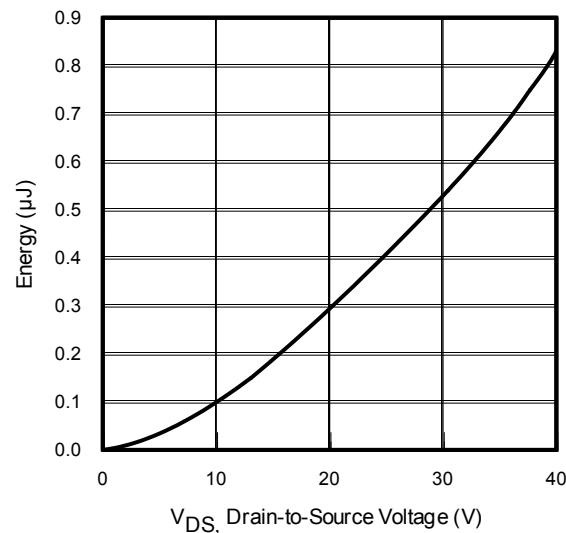


Fig 12. Typical C_{oss} Stored Energy

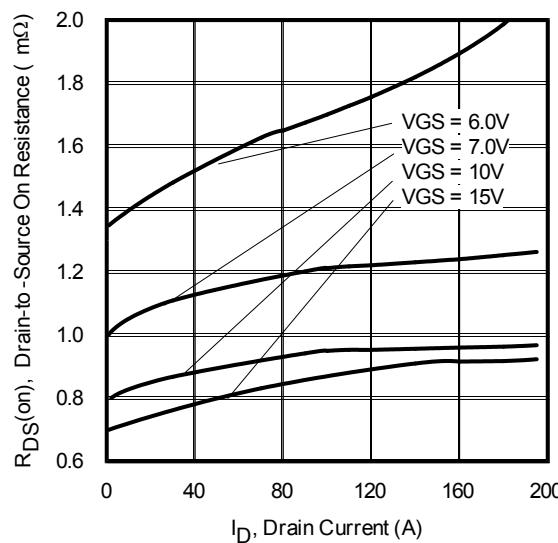


Fig 13. Typical On-Resistance vs. Drain Current

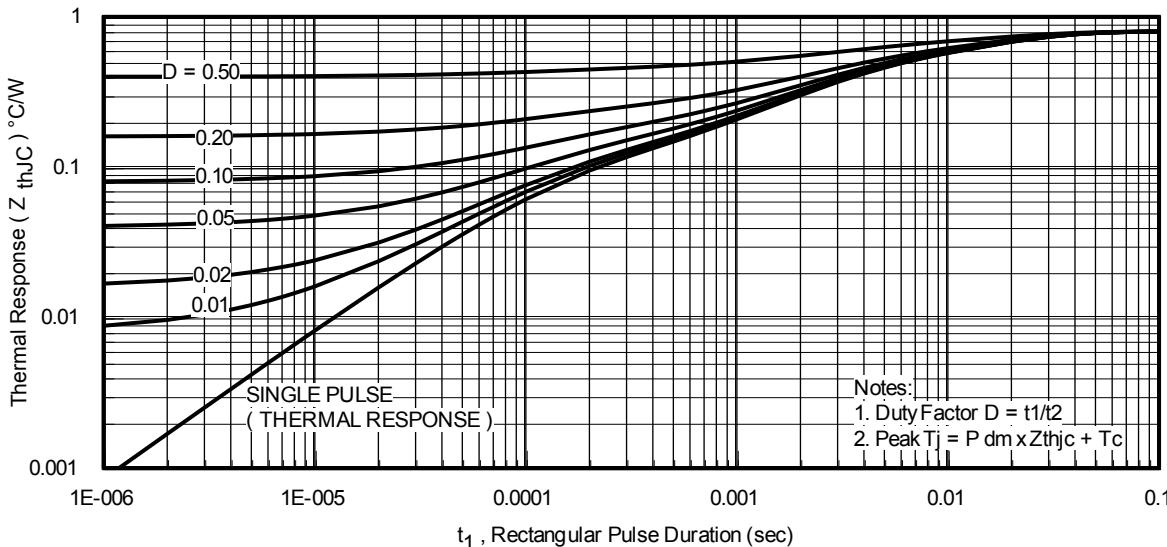


Fig 14. Maximum Effective Transient Thermal Impedance, Junction-to-Case

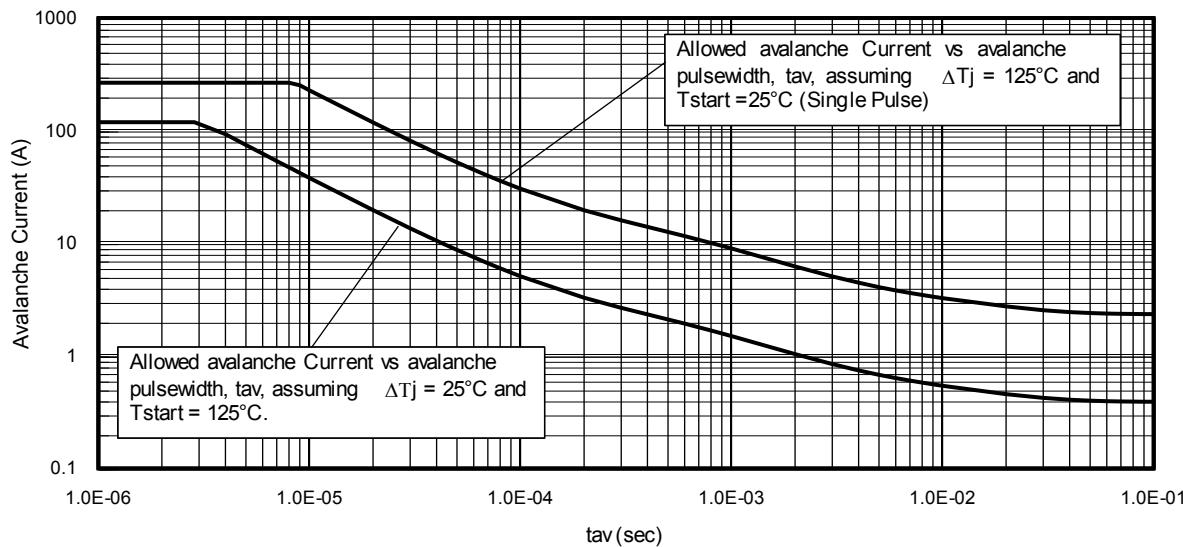


Fig 15. Typical Avalanche Current vs. Pulse width

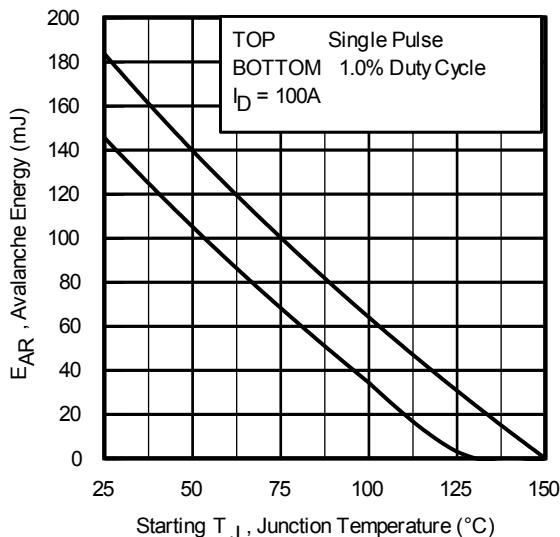
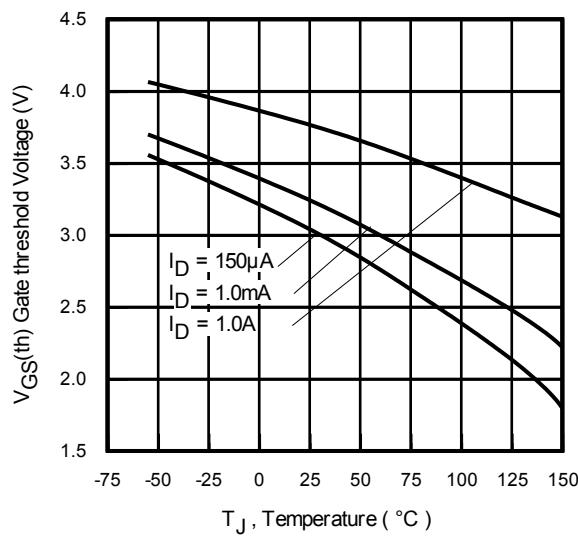
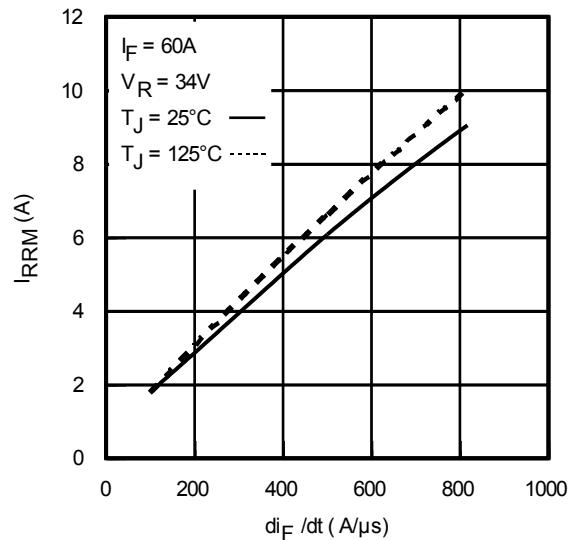
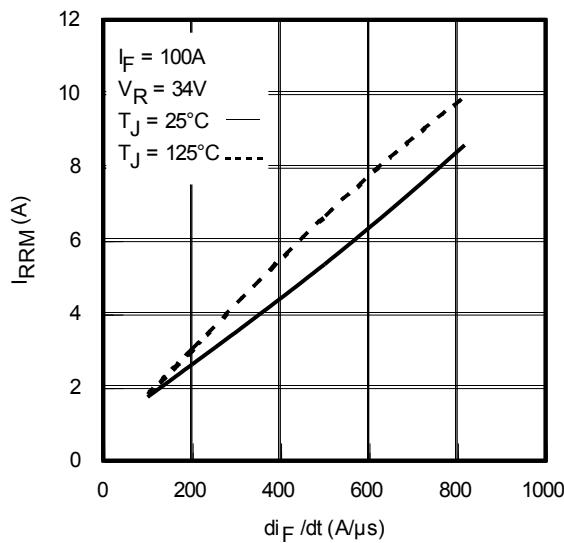
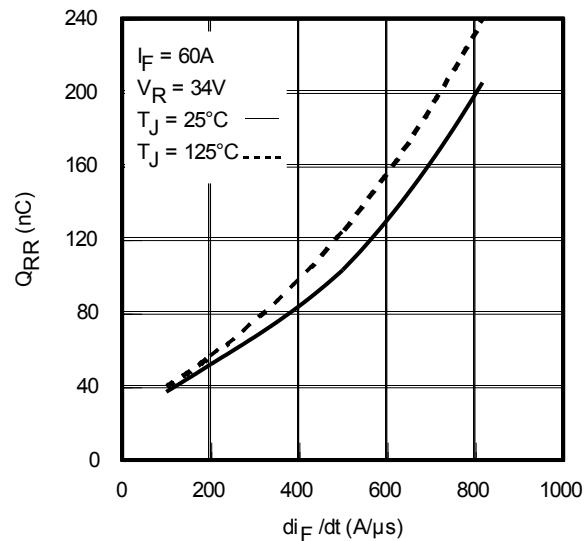
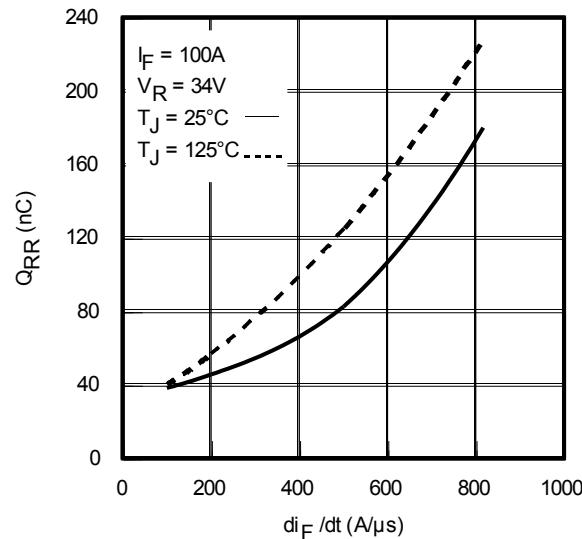


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

1. Avalanche failures assumption:
Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
4. $P_{D(ave)}$ = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6. I_{av} = Allowable avalanche current.
7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).
 t_{av} = Average time in avalanche.
 D = Duty cycle in avalanche = $t_{av} \cdot f$
 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)
 $PD(ave) = 1/2 \cdot (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$
 $I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$
 $EAS(AR) = P_{D(ave)} \cdot t_{av}$

**Fig 17.** Threshold Voltage vs. Temperature**Fig 18.** Typical Recovery Current vs. di/dt **Fig 19.** Typical Recovery Current vs. di/dt **Fig 20.** Typical Stored Charge vs. di/dt **Fig 21.** Typical Stored Charge vs. di/dt

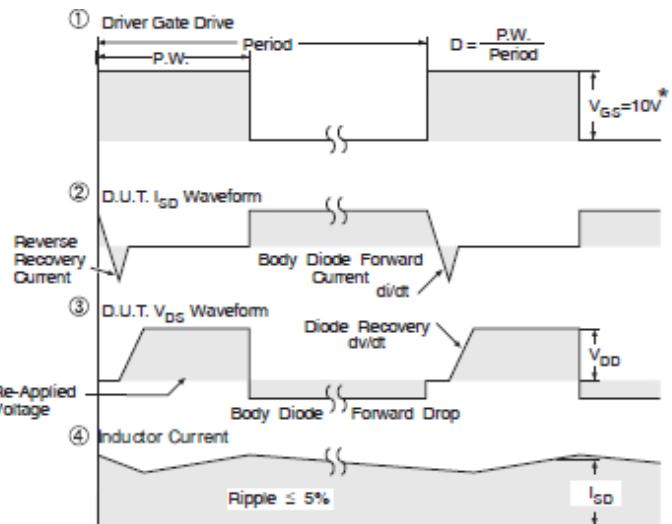
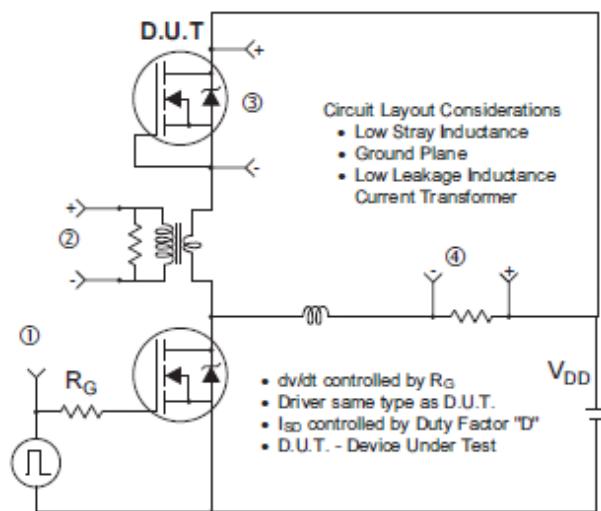


Fig 22. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

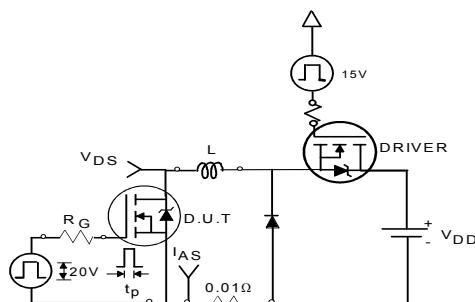


Fig 23a. Unclamped Inductive Test Circuit

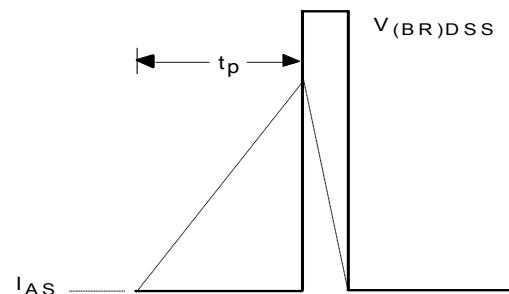


Fig 23b. Unclamped Inductive Waveforms

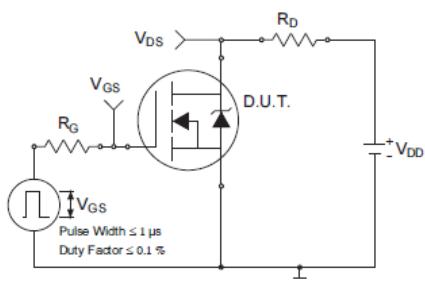


Fig 24a. Switching Time Test Circuit

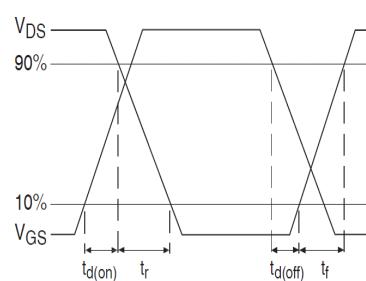


Fig 24b. Switching Time Waveforms

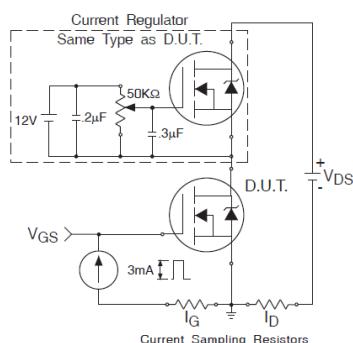


Fig 25a. Gate Charge Test Circuit

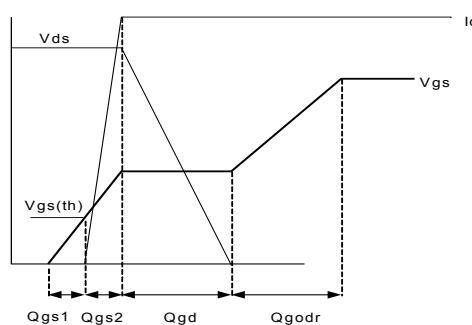
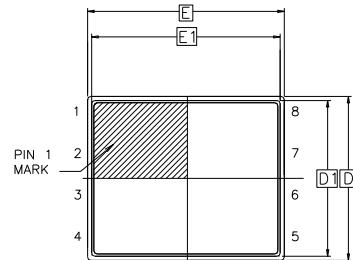
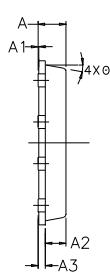


Fig 25b. Gate Charge Waveform

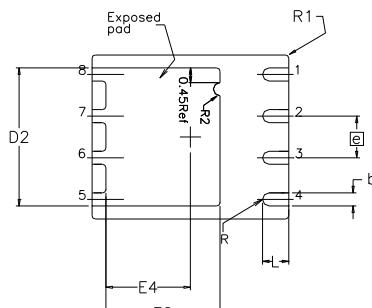
PQFN 5x6 Outline "B" Package Details



SIDE VIEW

TOP VIEW

SYMBOL	DIM	MIN	NOM	MAX
A	0.800	0.830	1.05	
A1	0.000	0.020	0.050	
A2	0.580	0.630	0.680	
A3		0.254	REF	
Ø	0°	10°	12°	
b	0.350	0.400	0.470	
D	4.850	5.000	5.150	
D1	4.675	4.750	5.000	
D2	3.700	4.210	4.300	
e		1.270	BSC	
E	5.850	6.000	6.150	
E1	5.675	5.750	6.000	
E2	3.380	3.480	3.760	
E4	2.480	2.580	2.680	
L	0.550	0.800	0.900	
R		0.200	REF	
R1		0.100	REF	
R2	0.150	0.200	0.250	

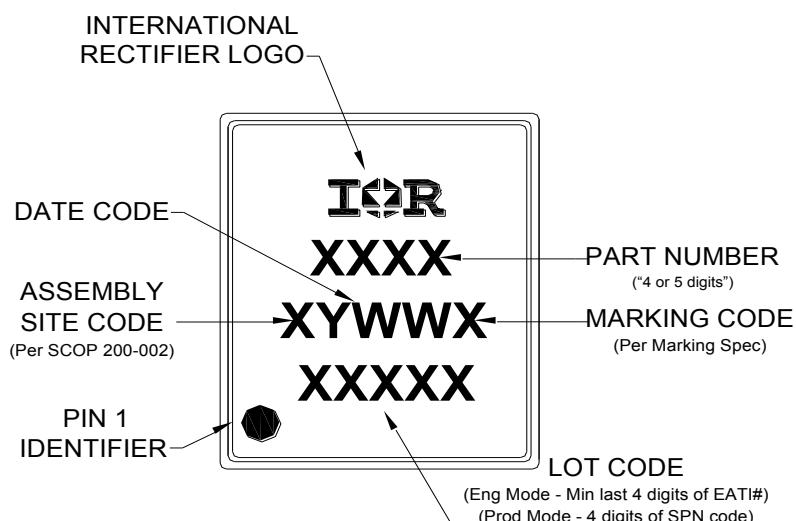


BOTTOM VIEW

For more information on board mounting, including footprint and stencil recommendation, please refer to application note AN-1136: <http://www.irf.com/technical-info/appnotes/an-1136.pdf>

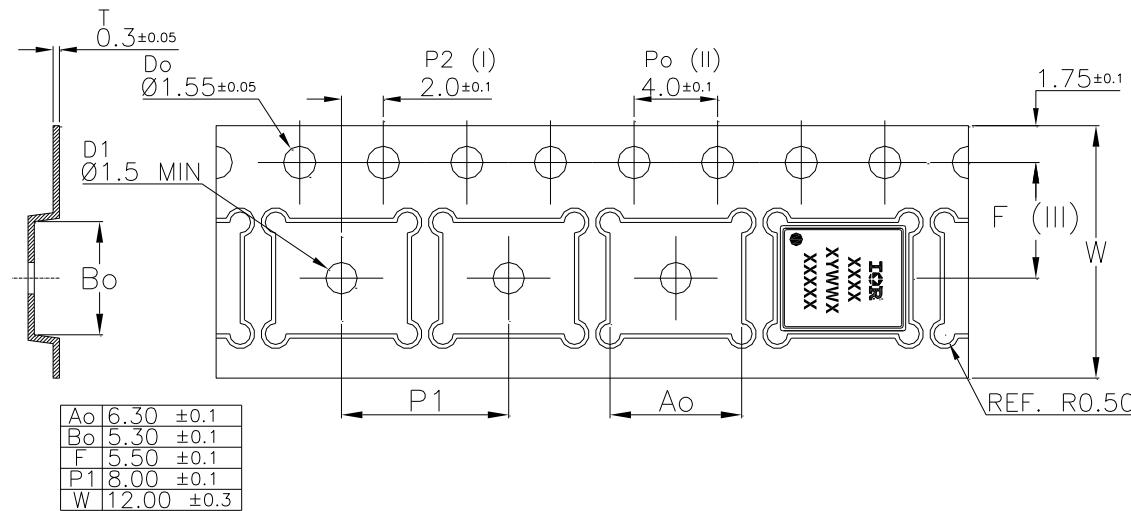
For more information on package inspection techniques, please refer to application note AN-1154: <http://www.irf.com/technical-info/appnotes/an-1154.pdf>

PQFN 5x6 Outline "B" Part Marking



Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

PQFN 5x6 Outline "B" Tape and Reel



Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

Qualification information[†]

Qualification level	Industrial ^{††}	
	(per JEDEC JESD47F ^{†††} guidelines)	
Moisture Sensitivity Level	PQFN 5mmx 6mm	MSL1 (per JEDEC J-STD-020D ^{†††})
RoHS compliant	Yes	

[†] Qualification standards can be found at International Rectifier's web site <http://www.irf.com/product-info/reliability>

^{††} Higher qualification ratings may be available should the user have such requirements. Please contact your International Rectifier sales representative for further information: <http://www.irf.com/whoto-call/salesrep/>

^{†††} Applicable version of JEDEC standard at the time of product release.

International
IR
Rectifier

IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA
To contact International Rectifier, please visit <http://www.irf.com/whoto-call/>